



The **IEEE International Integrated Reliability Workshop (IIRW)** focuses on ensuring electronic device reliability through fabrication, design, testing, characterization, and simulation, as well as identification of the defects and physical mechanisms responsible for reliability problems.

**October 11-14, 2021**

**Stanford Sierra  
Conference Center  
Fallen Leaf Lake,  
CA, USA**

**Abstract Deadline**  
July 09, 2020

**Late News Deadline**  
September 10, 2020

**General Chair:**  
Matthew Ring  
ON Semiconductor

**TPC Chair:**  
Matthew Hogan  
Mentor, A Siemens  
Business

**[www.iirw.org](http://www.iirw.org)**

### **IIRW 2021**

- Best Student Paper Award
- All accepted papers published in IEEEExplore
- Top 5-7 papers will be extended for publication in IEEE TDMR

### **Outstanding features** of the IIRW are

- Strong plenary, invited, and tutorial presentations
- Strong technical program (platform and posters)
- Unparalleled opportunities to meet leading experts
- Discussion and special interest groups sessions
- Unique rustic and secluded environment

### **IIRW 2021** welcomes abstracts related mainly to these topics

- FEOL/MOL/BEOL dielectrics (high- $k$ ,  $\text{SiO}_2$ ,  $\text{SiON}$ , low- $k$ )
- FET, FinFET, SOI, III-V, SiGe reliability (HC, BTI, TDD, etc.)
- Conventional and emerging memories (Flash, RRAM, etc.)
- Neuromorphic devices and circuits reliability
- Emerging technologies and devices (2D materials, IGZO, etc.)
- Power, wide-bandgap (SiC, GaN, etc.) devices reliability
- RF and mm/sub-mm Wave devices reliability
- Modeling and simulation of reliability, including self-heating
- Failure analysis and Advanced packaging reliability
- Impact of devices degradation on circuit reliability
- Design in reliability (products, circuits, systems, processes)
- Advanced automotive circuits, systems, products reliability
- Customer/manufacturer product reliability requirements
- Wafer-level reliability tests for monitoring and qualification

**Two-page abstract with representative data and figures should state clearly the results of your work and why they are significant.**

For more information please visit [www.iirw.org](http://www.iirw.org), or contact:  
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**Depending on the COVID-19 pandemic scenario  
IIRW 2021 could be virtual**